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(REV. 7-80)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.

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LIST OF DOCUMENTS CITED BY APPLICANT

(Use several sheets if necessary)

APPLICANT

Lee D. Whetsel

FILING DATE

October 20, 2003

GROUP

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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

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EXAMINER

C. Butt

DATE CONSIDERED

4-15-05

+EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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